MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PLED

AZ4208-01F-MS

Product specification





FEATURES

- 80W peak pulse power per line (tP = 8/20µs)
- DFN1006-2L package
- Replacement for MLV(0402)
- Bidirectional configurations
- Response time is typically < 1ns
- Low clamping voltage
- RoHS compliant
- Transient protection for data lines to IEC61000-4-2(ESD) ±30KV(air), ±30KV(contact); IEC61000-4-4 (EFT) 40A (5/50ns)

APPLICATIONS

- Cellular phones
- Portable devices
- Digital cameras
- Power supplies

Mechanical Characteristics

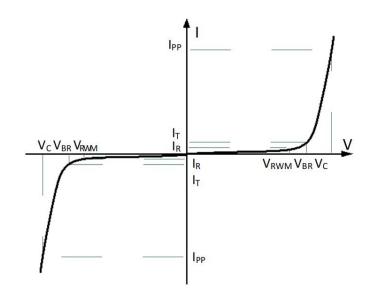
- Lead finish:100% matte Sn(Tin)
- Mounting position: Any
- Qualified max reflow temperature:260°C
- Device meets MSL 2 requirements
- Pure tin plating: 7 ~ 17 um
- Pin flatness:≤3mil

Reference News

PACKAGE OUTLINE	PIN CONFIGURATION	Marking		
	1 2	.b		
DFN-1006				

ElectronicsParameter

Symbol	Parameter		
Vrwm	Peak Reverse Working Voltage		
IR	Reverse Leakage Current @ VRWM		
V _{BR}	Breakdown Voltage @ I _T		
Iт	Test Current		
IPP	Maximum Reverse Peak Pulse Current		
Vc	Clamping Voltage @ IPP		
P _{PP}	Peak Pulse Power		
CJ	Junction Capacitance		
lF	Forward Current		
VF	Forward Voltage @ IF		





Electrical characteristics per line@25°C(unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Units
Peak Reverse Working Voltage	Vrwm				8	V
Breakdown Voltage	Vbr	lt = 1mA	9.0	11.0	13.0	V
Reverse Leakage Current	lr	V RWM = 5V T=25C			1.0	μA
Maximum Reverse Peak Pulse	IPP			5.0		А
Clamping Voltage	Vc	IPP=1A			13	V
Clamping Voltage	Vc	IPP=3A			15	V
Clamping Voltage	Vc	IPP=5A			17	V
Junction Capacitance	Cj	VR=0V f = 1MHz		13	15	pF

Absolute maximum rating@25°C

Rating	Symbol	Value	Units
Peak Pulse Power (t _p =8/20µs)	P _{pp}	80	W
Operating Temperature	TJ	-55 to + 150	°C
Storage Temperature	TSTTh	-55 to + 150	°C

Typical Characteristics

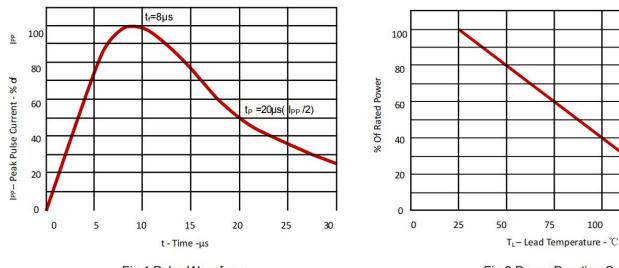
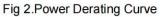


Fig 1.Pulse Waveform



100

125

150



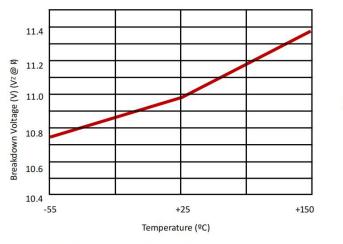


Fig 3.Typical Breakdown Voltage vs. Temperature

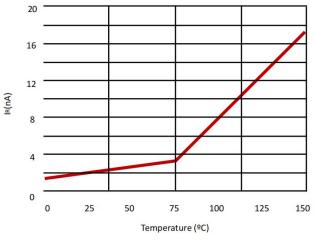


Fig 4. Typical Leakage Current vs. Temperature

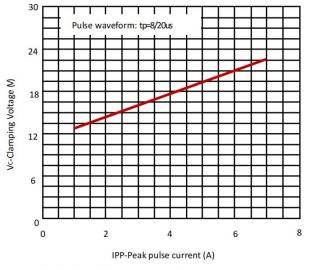


Fig 5. Clamping voltage vs. Peak pulse current

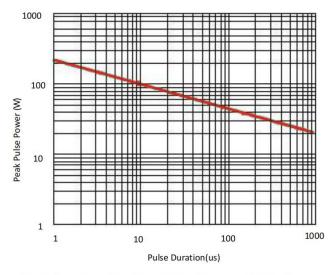
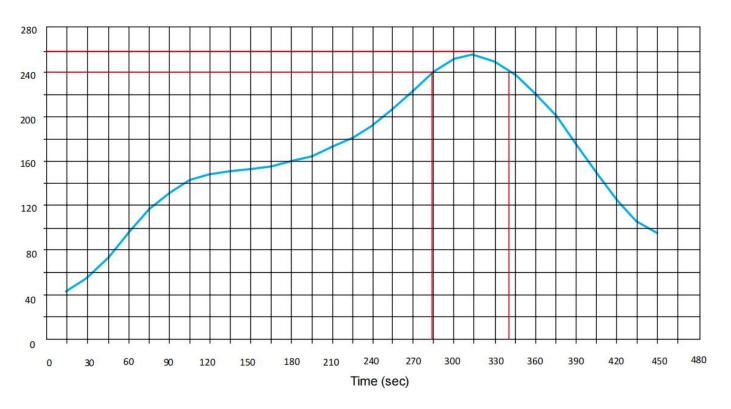


Fig 6. Non-Repetitive Peak Pulse Power vs. Pulse time



Solder Reflow Recommendation

Peak Temp=257°C, Ramp Rate=0.802deg. °C/sec



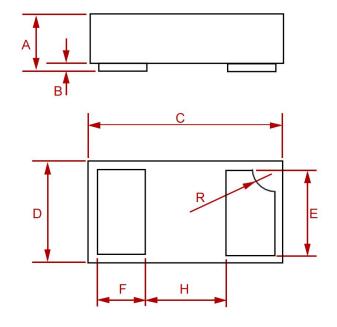
PCB Design

For TVS diodes a low-ohmic and low-inductive path to chassis earth is absolutely mandatory in order to achieve good ESD protection. Novices in the area of ESD protection should take following suggestions to heart:

- Do not use stubs, but place the cathode of the TVS diode directly on the signal trace.
- Do not make false economies and save copper for the ground connection.
- Place via holes to ground as close as possible to the anode of the TVS diode.
- Use as many via holes as possible for the ground connection.
- Keep the length of via holes in mind! The longer the more inductance they will have.

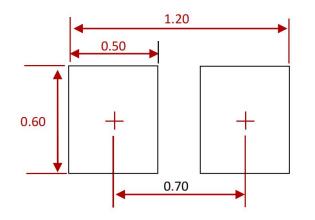


PACKAGE MECHANICAL DATA



	Inch		Millimeters		
Dim	MIN	MAX	MIN	MAX	
Α	0.0125	0.02	0.32	0.52	
В	0.000	0.002	0.00	0.05	
C	0.037	0.043	0.95	1.080	
D	0.022	0.027	0.55	0.680	
E	0.016	0.024	0.40	0.60	
F	0.008	0.012	0.20	0.30	
н	0.015Typ.		0.40Тур.		
R	0.001	0.005	0.05	0. 15	

Suggested Pad Layout



NOTES:

1. CONTROLLING DIMENSIONS ARE IN MILLIMETERS (ANGLES IN DEGREES).

2. THIS LAND PATTERN IS FOR REFERENCE PURPOSES ONLY. CONSULT YOUR MANUFACTURING GROUP TO ENSURE YOUR COMPANY'S MANUFACTURING GUIDELINES ARE MET.

REEL SPECIFICATION

P/N	PKG	QTY
AZ4208-01F-MS	DFN-1006	12000



Attention

■ Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.

MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all MSKSEMI Semiconductor products described or contained herein.

Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.

MSKSEMI Semiconductor. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with someprobability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits anderror prevention circuits for safedesign, redundant design, and structural design.

■ In the event that any or all MSKSEMI Semiconductor products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from theauthorities concerned in accordance with the above law.

■ No part of this publication may be reproduced or transmitted in any form or by any means, electronic or

mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.

Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements intellectual property rights or other rights of third parties.

Any and all information described or contained herein are subject to change without notice due to

product/technology improvement, etc. Whendesigning equipment, referto the "Delivery Specification" for the MSKSEMI Semiconductor productthat you intend to use.